Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/687,643	MINO, TETSUYA	
Examiner	Art Unit	
Paul D. Kim	3729	

SEARCHED					
Class	Subclass	Date	Examiner		
29	603.11 603.13- 603.16 603.18	7/5/2005	PK		
360	121 122	7/5/2005	PK		
	126 317				
427	127 128				
204	192.32- 19	7/5/2005	PK		
216	22				
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
Reviewed Parent Application 09/150,206 (US PAT. 6,188,544) 09/734,758 (ABN)	7/5/2005	PK			
Textr Search EAST/NPL (IEEE)	7/6/2005	PK			
Updated Text Search (EAST)	11/14/2005	PK			